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**Application Number** 10/046,926 Substitute for form 1449A/PTO 1/13/02 **Filing Date** INFORMATION DISCLOSURE **First Named Inventor** Steven Teig STATEMENT BY APPLICANT **Group Art Unit** (use as many sheets as necessary) **Examiner Name** SPLX.P0085 Sheet 1 1 Attorney Docket Number

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<sup>\*</sup> EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. Applicant's unique citation designation number(optional). See Kinds Codes of USPTO Patent Documents at <a href="https://www.uspto.gov">www.uspto.gov</a> or MPEP 901.04. Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. Applicant is to place a check mark here if English language Translation is attached.

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				RELATED	J.S. PATENT DOCU	IMENTS
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		2.	2003/0018947	12-07-2001	Steven Teig et al.	Application with some of the same parent provisional applications and with the same specification as the present application except for summary and abstract.
		3.	2002/0147958	10-19-2001	Steven Teig et al.	Parent application per the preliminary amendment dated 2/19/03.
		4.	2003/0063614	01-04-2002	Steven Teig et al.	Application with some of the same parent provisional applications and with the same specification as the present application except for summary and abstract.
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<u></u> -		6. 2003/0063568		01-04-2002	Steven Teig et al.	Application with some of the same parent provisional applications and with the same specification as the present application except for summary and abstract.
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VS	•	13.	2003/0088844	01-07-2002	Steven Teig et al.	Per the preliminary amendment dated 5/7/03, the present application is a continuation of 2003/0088844, which is a continuation of 2003/0079193.

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<sup>&</sup>lt;sup>1</sup> Unique citation designation number. <sup>2</sup> See attached Kinds of U.S. Patent Documents. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>6</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

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<sup>&</sup>lt;sup>1</sup> Unique citation designation number. <sup>2</sup> See attached Kinds of U.S. Patent Documents. <sup>3</sup> Enter Office that Issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

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First Named Inventor

Steven Teig

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		OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS	
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